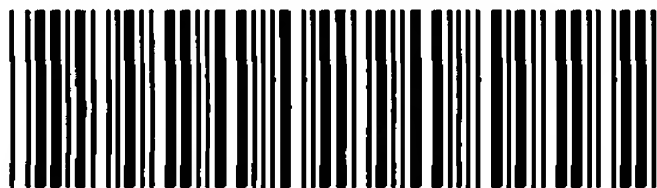


**Search Notes**

Application/Control No.

10/628,640

Examiner

X. L. Bautista

Applicant(s)/Patent under  
Reexamination

STAUTNER ET AL.

Art Unit

2179

**SEARCHED**

Class	Subclass	Date	Examiner
715	500.1	8/29/2007	XB
	501.1		
715	716-718		
	720-723		
	733,762		
	765,810		
	825,835		
	840,854		
	855,962		
725	37-40,42		
	48,51		
	59-61,64		
707	1,10,100		
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**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	716-721	8/30/2007	XB
	733,810		
	835,855		
725/37,39,40,42,48,51, 59,61			

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search	8/29/2007	XB
Databases Searched: US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB		
Google Search	8/30/2007	
IEEE Search		